

5-25-04

ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of Invention	INCREASE PRODUCTIVITY AT WAFER TEST USING PROBE RETEST DATA ANALYSIS						
<p>Application Number : 10/709,721</p> <p>Confirmation Number:</p> <p>First Named Applicant: Akiko Balchiunas</p> <p>Attorney Docket Number: BUR920040137US1</p> <p>Art Unit: 2829</p> <p>Examiner: TANG</p> <p>Search string: (6240329 or 6350959 or 6507800 or 6618682 or 20030120445 or 20030139839).pn</p>							
US Patent Documents							
Note: Applicant is not required to submit a paper copy of cited US Patent Documents							
init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
MT	1	6240329	2001-05-29	Sun			
	2	6350959	2002-02-26	Beffa			
	3	6507800	2003-01-14	Sheu			
MT	4	6618682	2003-08-09	Bulaga et al.			
9							
US Published Applications							
Note: Applicant is not required to submit a paper copy of cited US Published Applications							
init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
MT	1	20030120445	2003-06-26	Barbour et al.			
MT	2	20030139839	2003-07-24	Beffa			
Signature							
Examiner Name				Date			
				7/25/06			

KRH
4-20-07